

Notice of References Cited	Application/Control No. 10/767,726	Applicant(s)/Patent Under Reexamination OGAWA, HIDEHIKO	
	Examiner Thomas D. Lee	Art Unit 2625	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,742,769	04-1998	Lee et al.	709/206
*	B	US-5,798,845	08-1998	Baek et al.	358/434
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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